

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/077,280	02/14/2002	Ping-Ling Fan	67,200-671	3287
75	90 01/26/2005		EXAMINER	
TUNG & ASSOCIATES			GUADALUPE, YARITZA	
Suite 120 838 W. Long Lake Road			ART UNIT	PAPER NUMBER
Bloomfield Hills, MI 48302			2859	
			DATE MAILED: 01/26/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

U.S. Patent and	Trademark Office
PTOL-326 ((Rev. 1-04)

1) Notice of References Cited (PTO-892)

Paper No(s)/Mail Date _

2) Notice of Draftsperson's Patent Drawing Review (PTO-948)

Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)

Attachment(s)

4) Interview Summary (PTO-413)

6) U Other: _____.

Paper No(s)/Mail Date. ___

5) Notice of Informal Patent Application (PTO-152)

Application/Control Number: 10/077,280

Art Unit: 2859

DETAILED ACTION

In response to Request for Continued Examination filed July 12, 2004

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 21 22 are rejected under 35 U.S.C. 102 (b) as being anticipated by Admitted Prior Art [Hereinafter APA].

With respect to claims 21 - 22: APA discloses an apparatus comprising a gauge (92) for measuring a gap (considered a horizontal gap gauge due to its orientation as shown in Figure 4, having a horizontal extension which could define a threshold for the gap to be measured) between said baffle and the chamber wall (See Figure 4 and page 13, lines 1 - 5 of the Specification) in order to level said electrostatic chuck, which can be also translated into prevention of peeling or damaging said chamber wall. APA discloses an apparatus for use in various semiconductor fabrication operation, e.g., wet cleaning semiconductor operation. APA further discloses the use of dual rotate magnets (DRM) (See Figure 4, # 10 and 11), a focus ring (20), and said electrostatic chuck having a horizontal or vertical movement.

Application/Control Number: 10/077,280 Page 3

Art Unit: 2859

Allowable Subject Matter

3. Claims 1-15 and 17-20 are allowed.

The following is an examiner's statement of reasons for allowance:

- a. Claims 1 10 are allowable over the Prior Art of Record because it fails to teach or suggest a gauge apparatus for use in a semiconductor system, said apparatus comprising a leveling mechanism for measuring s horizontal gap between said baffle and said chamber wall, the leveling mechanism disposed between said electrostatic chuck at said second position of said electrostatic chuck and said chamber wall in combination with the remaining limitations of the claims.
- b. Claims 11 15 and 17 20 are allowable over the Prior Art of Record because it fails to teach or suggest a method for preventing damage to a chamber wall by a baffle plate in a semiconductor fabrication system, said method comprising the step of measuring a horizontal or vertical gap using a gauge having a leveling mechanism and a modified portion in combination with the remaining limitations of the claims.

Application/Control Number: 10/077,280 Page 4

Art Unit: 2859

Response to Arguments

4. Applicant's arguments regarding claims 21 – 22 filed December 13, 2004 have been fully

considered but they are not persuasive.

Applicant arguments regarding the APA not teaching a horizontal gap gauge is not

persuasive. As previously indicated by the Examiner, the gauge (92) disclosed by APA sets

forth a horizontal gap gauge. APA (See Figure 4) shows an ESC (34) and a gauge (92)

having a horizontal extension which could define a threshold for the gap to be measured,

therefore, defining a horizontal gap gauge as indicated in the rejection above.

5. Applicant's arguments, see remarks, filed December 13, 2004, with respect to claims 1 –

15 and 17 - 20 have been fully considered and are persuasive. The rejection to the claims has

been withdrawn and claims have been indicated as allowable.

Conclusion

6. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time

policy as set forth in 37 CFR 1.136(a).

Application/Control Number: 10/077,280

Art Unit: 2859

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Page 5

Any inquiry concerning this communication or earlier communications from the 7. examiner should be directed to Yaritza Guadalupe McCall whose telephone number is (571)272 -2244. The examiner can normally be reached on 8:00 AM - 5:30 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Diego F.F. Gutierrez can be reached on (571) 272-2245. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Art Unit: 2859

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

YGM January 21, 2005 Yaritza Guadalupe-McCall
Patent Examiner
Art Unit 2859

usa Gradalyeldlall